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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1694
Number of Logic Elements/Cells	33880
Total RAM Bits	1369728
Number of I/O	500
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s30f672c3n

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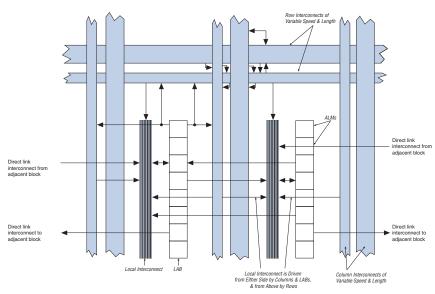


Figure 2-2. Stratix II LAB Structure

LAB Interconnects

The LAB local interconnect can drive ALMs in the same LAB. It is driven by column and row interconnects and ALM outputs in the same LAB. Neighboring LABs, M512 RAM blocks, M4K RAM blocks, M-RAM blocks, or DSP blocks from the left and right can also drive an LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher performance and flexibility. Each ALM can drive 24 ALMs through fast local and direct link interconnects. Figure 2–3 shows the direct link connection.

C16 column interconnects span a length of 16 LABs and provide the fastest resource for long column connections between LABs, TriMatrix memory blocks, DSP blocks, and IOEs. C16 interconnects can cross M-RAM blocks and also drive to row and column interconnects at every fourth LAB. C16 interconnects drive LAB local interconnects via C4 and R4 interconnects and do not drive LAB local interconnects directly.

All embedded blocks communicate with the logic array similar to LAB-to-LAB interfaces. Each block (that is, TriMatrix memory and DSP blocks) connects to row and column interconnects and has local interconnect regions driven by row and column interconnects. These blocks also have direct link interconnects for fast connections to and from a neighboring LAB. All blocks are fed by the row LAB clocks, labclk [5..0].

Table 2–2 shows the Stratix II device's routing scheme.

Table 2–2. Stratix II Device	Rou	ting S	Schen	ne (l	Part 1	of 2)									
							[Destii	natio	n						
Source	Shared Arithmetic Chain	Carry Chain	Register Chain	Local Interconnect	Direct Link Interconnect	R4 Interconnect	R24 Interconnect	C4 Interconnect	C16 Interconnect	ALM	M512 RAM Block	M4K RAM Block	M-RAM Block	DSP Blocks	Column 10E	Row 10E
Shared arithmetic chain										✓						
Carry chain										✓						
Register chain										✓						
Local interconnect										✓	✓	✓	\	\	\	✓
Direct link interconnect				\												
R4 interconnect				✓		✓	✓	✓	✓							
R24 interconnect						✓	✓	✓	✓							
C4 interconnect				✓		✓		✓								
C16 interconnect						✓	✓	✓	✓							
ALM	✓	\	\	\	✓	\		\								
M512 RAM block				✓	✓	✓		✓								
M4K RAM block				✓	✓	✓		✓								
M-RAM block					✓	✓	✓	✓								
DSP blocks					✓	✓		✓								

							[Destir	natio	n						
Source	Shared Arithmetic Chain	Carry Chain	Register Chain	Local Interconnect	Direct Link Interconnect	R4 Interconnect	R24 Interconnect	C4 Interconnect	C16 Interconnect	ALM	M512 RAM Block	M4K RAM Block	M-RAM Block	DSP Blocks	Column 10E	Row IDE
Column IOE					✓			✓	✓							
Row IOE					/	/	/	/								

TriMatrix Memory

TriMatrix memory consists of three types of RAM blocks: M512, M4K, and M-RAM. Although these memory blocks are different, they can all implement various types of memory with or without parity, including true dual-port, simple dual-port, and single-port RAM, ROM, and FIFO buffers. Table 2–3 shows the size and features of the different RAM blocks.

Table 2–3. TriMatrix Memor	y Features (Part 1 of 2)		
Memory Feature	M512 RAM Block (32 × 18 Bits)	M4K RAM Block (128 × 36 Bits)	M-RAM Block (4K × 144 Bits)
Maximum performance	500 MHz	550 MHz	420 MHz
True dual-port memory		✓	✓
Simple dual-port memory	✓	✓	✓
Single-port memory	✓	✓	✓
Shift register	✓	✓	
ROM	✓	✓	(1)
FIFO buffer	✓	✓	✓
Pack mode		✓	✓
Byte enable	✓	✓	✓
Address clock enable		✓	✓
Parity bits	✓	✓	✓
Mixed clock mode	✓	✓	✓
Memory initialization (.mif)	✓	✓	

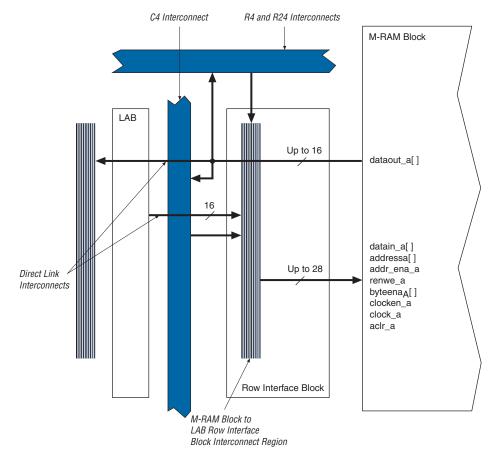


Figure 2-26. M-RAM Row Unit Interface to Interconnect

Table 2–4 shows the input and output data signal connections along with the address and control signal input connections to the row unit interfaces (L0 to L5 and R0 to R5).

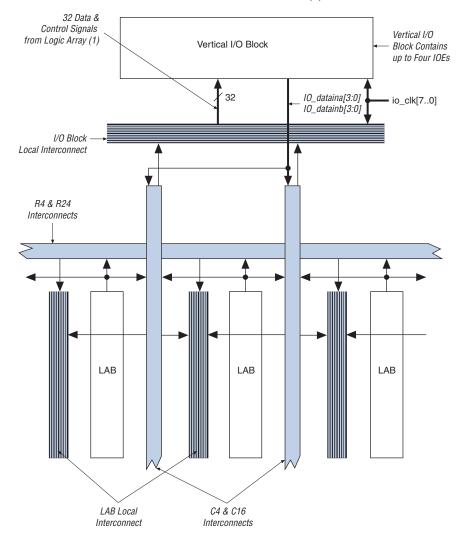


Figure 2–48. Column I/O Block Connection to the Interconnect Note (1)

Note to Figure 2-48:

(1) The 32 data and control signals consist of eight data out lines: four lines each for DDR applications io_dataouta[3..0] and io_dataoutb[3..0], four output enables io_oe[3..0], four input clock enables io_ce_in[3..0], four output clock enables io_ce_out[3..0], four clocks io_clk[3..0], four asynchronous clear and preset signals io_aclr/apreset[3..0], and four synchronous clear and preset signals io sclr/spreset[3..0].

Table 2-25. E	P2\$130 Differe	ential Chan	nels	Note (1)							
Dookono	Transmitter/	Total		Center F	ast PLLs		Corner Fast PLLs (4)				
Package	Receiver	Channels	PLL 1	PLL 2	PLL 3	PLL 4	PLL 7	PLL 8	PLL 9	PLL 10	
780-pin	Transmitter	64 (2)	16	16	16	16	-	-	-		
FineLine BGA		(3)	32	32	32	32	-	-	-	-	
	Receiver	68 (2)	17	17	17	17	-	-	-	-	
		(3)	34	34	34	34	-	-	-		
1,020-pin	Transmitter	88 (2)	22	22	22	22	22	22	22	22	
FineLine BGA		(3)	44	44	44	44	-	-	-	-	
	Receiver	92 (2)	23	23	23	23	23	23	23	23	
		(3)	46	46	46	46	-	-	-	-	
1,508-pin	1,508-pin Transmitter	156 <i>(2)</i>	37	41	41	37	37	41	41	37	
FineLine BGA		(3)	78	78	78	78	-	-	-	-	
	Receiver	156 <i>(2)</i>	37	41	41	37	37	41	41	37	
		(3)	78	78	78	78	-	-	-	-	

Table 2–26. E	P2\$180 Differe	ential Chan	nels	Note (1)						
Dookogo	Transmitter/	Total		Center F	ast PLLs	1	Corner Fast PLLs (4)			
Package	Receiver	Channels	PLL 1	PLL 2	PLL 3	PLL 4	PLL 7	PLL 8	PLL 9	PLL 10
1,020-pin FineLine BGA 1,508-pin	Transmitter	88 (2)	22	22	22	22	22	22	22	22
FineLine BGA	FineLine BGA	(3)	44	44	44	44	-	-	-	-
	Receiver	92 (2)	23	23	23	23	23	23	23	23
		(3)	46	46	46	46	-	=	-	-
1,508-pin	Transmitter	156 <i>(2)</i>	37	41	41	37	37	41	41	37
FineLine BGA		(3)	78	78	78	78	-	=	-	-
	Receiver	156 <i>(2)</i>	37	41	41	37	37	41	41	37
		(3)	78	78	78	78	-	-	-	-

Notes to Tables 2-21 to 2-26:

- (1) The total number of receiver channels includes the four non-dedicated clock channels that can be optionally used as data channels.
- (2) This is the maximum number of channels the PLLs can directly drive.
- (3) This is the maximum number of channels if the device uses cross bank channels from the adjacent center PLL.
- (4) The channels accessible by the center fast PLL overlap with the channels accessible by the corner fast PLL. Therefore, the total number of channels is not the addition of the number of channels accessible by PLLs 1, 2, 3, and 4 with the number of channels accessible by PLLs 7, 8, 9, and 10.

The Quartus II software has an Auto Usercode feature where you can choose to use the checksum value of a programming file as the JTAG user code. If selected, the checksum is automatically loaded to the USERCODE register. Turn on the **Auto Usercode** option by clicking **Device & Pin Options**, then **General**, in the **Settings** dialog box (Assignments menu).

Table 3–2. Stratix II Boundary-Scan Register Length							
Device	Boundary-Scan Register Length						
EP2S15	1,140						
EP2S30	1,692						
EP2S60	2,196						
EP2S90	2,748						
EP2S130	3,420						
EP2S180	3,948						

Table 3–3. 32	Table 3–3. 32-Bit Stratix II Device IDCODE											
		IDCODE (32	Bits) (1)									
Device	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit) (2)								
EP2S15	0000	0010 0000 1001 0001	000 0110 1110	1								
EP2S30	0000	0010 0000 1001 0010	000 0110 1110	1								
EP2S60	0001	0010 0000 1001 0011	000 0110 1110	1								
EP2S90	0000	0010 0000 1001 0100	000 0110 1110	1								
EP2S130	0000	0010 0000 1001 0101	000 0110 1110	1								
EP2S180	0000	0010 0000 1001 0110	000 0110 1110	1								

Notes to Table 3-3:

- (1) The most significant bit (MSB) is on the left.
- (2) The IDCODE's least significant bit (LSB) is always 1.



Stratix, Stratix II, Cyclone, and Cyclone II devices must be within the first 17 devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Stratix, Stratix II, Cyclone, and Cyclone II devices are in the 18th or after they fail configuration. This does not affect SignalTap II.

you need to support configuration input voltages of 1.8 V/1.5 V, you should set the VCCSEL to a logic high and the V_{CCIO} of the bank that contains the configuration inputs to 1.8 V/1.5 V.



For more information on multi-volt support, including information on using TDO and nCEO in multi-volt systems, refer to the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Configuration Schemes

You can load the configuration data for a Stratix II device with one of five configuration schemes (see Table 3–5), chosen on the basis of the target application. You can use a configuration device, intelligent controller, or the JTAG port to configure a Stratix II device. A configuration device can automatically configure a Stratix II device at system power-up.

You can configure multiple Stratix II devices in any of the five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Stratix II FPGAs offer the following:

- Configuration data decompression to reduce configuration file storage
- Design security using configuration data encryption to protect your designs
- Remote system upgrades for remotely updating your Stratix II designs

Table 3–5 summarizes which configuration features can be used in each configuration scheme.

Configuration Scheme	Configuration Method	Design Security	Decompression	Remote System Upgrade
FPP	MAX II device or microprocessor and flash device	√ (1)	√ (1)	✓
	Enhanced configuration device		√ (2)	~
AS	Serial configuration device	✓	✓	√ (3)
PS	MAX II device or microprocessor and flash device	✓	~	✓
	Enhanced configuration device	✓	✓	✓
	Download cable (4)	✓	✓	

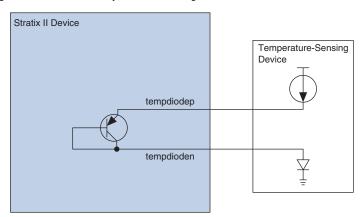


Figure 3-1. External Temperature-Sensing Diode

Table 3–6 shows the specifications for bias voltage and current of the Stratix II temperature sensing diode.

Table 3–6. Tempe	erature-Sensing	Diode Electrica	l Characteristic	s
Parameter	Minimum	Typical	Maximum	Unit
IBIAS high	80	100	120	μΑ
IBIAS low	8	10	12	μΑ
VBP - VBN	0.3		0.9	V
VBN		0.7		V
Series resistance			3	Ω

the Device & Pin Options dialog box in the Quartus II software uses a 32-bit CRC circuit to ensure data reliability and is one of the best options for mitigating SEU.

You can implement the error detection CRC feature with existing circuitry in Stratix II devices, eliminating the need for external logic. For Stratix II devices, CRC is computed by the device during configuration and checked against an automatically computed CRC during normal operation. The CRC_ERROR pin reports a soft error when configuration SRAM data is corrupted, triggering device reconfiguration.

Custom-Built Circuitry

Dedicated circuitry is built in the Stratix II devices to perform error detection automatically. This error detection circuitry in Stratix II devices constantly checks for errors in the configuration SRAM cells while the device is in user mode. You can monitor one external pin for the error and use it to trigger a re-configuration cycle. You can select the desired time between checks by adjusting a built-in clock divider.

Software Interface

In the Quartus II software version 4.1 and later, you can turn on the automated error detection CRC feature in the Device & Pin Options dialog box. This dialog box allows you to enable the feature and set the internal frequency of the CRC between 400 kHz to 50 MHz. This controls the rate that the CRC circuitry verifies the internal configuration SRAM bits in the FPGA device.

For more information on CRC, refer to AN 357: Error Detection Using CRC in Altera FPGA Devices.

Document Revision History

Table 3–7 shows the revision history for this chapter.

Table 3–7. Dod	cument Revision History (Part 1 of 2)	
Date and Document Version	Changes Made	Summary of Changes
May 2007, v4.2	Moved Document Revision History section to the end of the chapter.	_
	Updated the "Temperature Sensing Diode (TSD)" section.	_

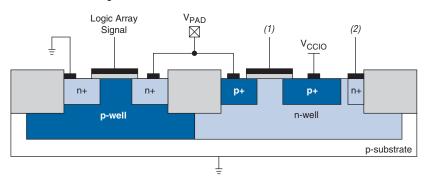


Figure 4–2. Transistor Level Diagram of FPGA Device I/O Buffers

Notes to Figure 4–2:

- This is the logic array signal or the larger of either the V_{CCIO} or V_{PAD} signal.
- This is the larger of either the V_{CCIO} or V_{PAD} signal.

Power-On Reset Circuitry

Stratix II devices have a POR circuit to keep the whole device system in reset state until the power supply voltage levels have stabilized during power-up. The POR circuit monitors the $V_{\rm CCINT}$, $V_{\rm CCIO}$, and $V_{\rm CCPD}$ voltage levels and tri-states all the user I/O pins while $V_{\rm CC}$ is ramping up until normal user levels are reached. The POR circuitry also ensures that all eight I/O bank $V_{\rm CCIO}$ voltages, $V_{\rm CCPD}$ voltage, as well as the logic array $V_{\rm CCINT}$ voltage, reach an acceptable level before configuration is triggered. After the Stratix II device enters user mode, the POR circuit continues to monitor the $V_{\rm CCINT}$ voltage level so that a brown-out condition during user mode can be detected. If there is a $V_{\rm CCINT}$ voltage sag below the Stratix II operational level during user mode, the POR circuit resets the device.

When power is applied to a Stratix II device, a power-on-reset event occurs if V_{CC} reaches the recommended operating range within a certain period of time (specified as a maximum V_{CC} rise time). The maximum V_{CC} rise time for Stratix II device is 100 ms. Stratix II devices provide a dedicated input pin (PORSEL) to select POR delay times of 12 or 100 ms during power-up. When the PORSEL pin is connected to ground, the POR time is 100 ms. When the PORSEL pin is connected to V_{CC} , the POR time is 12 ms.

Table 5-	4. Stratix II Device DC Op	erating Conditions	(Part 2 of 2)	Note (1)			
Symbol	Parameter	Conditio	ns	Minimum	Typical	Maximum	Unit
I _{CCI00}	V _{CCIO} supply current	V_I = ground, no	EP2S15		4.0	(3)	mA
	(standby)	load, no toggling inputs	EP2S30		4.0	(3)	mA
		T _J = 25° C	EP2S60		4.0	(3)	mA
			EP2S90		4.0	(3) m (50 k 70 k 100 k 150 k	mA
			EP2S130		4.0	(3)	mA
			EP2S180		4.0	(3)	mA
R _{CONF} (4)	Value of I/O pin pull-up	Vi = 0; V _{CCIO} = 3.3 V	10	25	50	kΩ	
	resistor before and during configuration	Vi = 0; V _{CCIO} = 2.5 V	/	15	35	(3) m/ (3) m/ (3) m/ (3) m/ (3) m/ (3) m/ 50 kΩ 70 kΩ 100 kΩ 150 kΩ	kΩ
		Vi = 0; V _{CCIO} = 1.8 V	/	30	50		kΩ
		Vi = 0; V _{CCIO} = 1.5 V	/	40	75		kΩ
		Vi = 0; V _{CCIO} = 1.2 V	/	50	90	170	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration				1	2	kΩ

Notes to Table 5-4:

- (1) Typical values are for T_A = 25°C, V_{CCINT} = 1.2 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.
- (2) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).
- (3) Maximum values depend on the actual T_J and design utilization. See the Excel-based PowerPlay Early Power Estimator (available at www.altera.com) or the Quartus II PowerPlay Power Analyzer feature for maximum values. See the section "Power Consumption" on page 5–20 for more information.
- (4) Pin pull-up resistance values are lower if an external source drives the pin higher than V_{CCIO}.

I/O Standard Specifications

Tables 5–5 through 5–32 show the Stratix II device family I/O standard specifications.

Table 5–5. LVTTL Specifications (Part 1 of 2)										
Symbol	Parameter	Conditions	Minimum	Maximum	Unit					
V _{CCIO} (1)	Output supply voltage		3.135	3.465	V					
V _{IH}	High-level input voltage		1.7	4.0	V					
V _{IL}	Low-level input voltage		-0.3	0.8	V					
V _{OH}	High-level output voltage	I _{OH} = -4 mA (2)	2.4		V					

Table 5-1	Table 5–12. LVPECL Specifications											
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit						
V _{CCIO} (1)	I/O supply voltage		3.135	3.300	3.465	V						
V _{ID}	Input differential voltage swing (single-ended)		300	600	1,000	mV						
V _{ICM}	Input common mode voltage		1.0		2.5	٧						
V _{OD}	Output differential voltage (single-ended)	R _L = 100 Ω	525		970	mV						
V _{OCM}	Output common mode voltage	R _L = 100 Ω	1,650		2,250	mV						
R _L	Receiver differential input resistor		90	100	110	Ω						

Note to Table 5-12:

(1) The top and bottom clock input differential buffers in I/O banks 3, 4, 7, and 8 are powered by V_{CCINT} , not V_{CCIO} . The PLL clock output/feedback differential buffers are powered by VCC_PLL_OUT. For differential clock output/feedback operation, VCC_PLL_OUT should be connected to 3.3 V.

Table 5–1	Table 5–13. HyperTransport Technology Specifications											
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit						
V _{CCIO}	I/O supply voltage for left and right I/O banks (1, 2, 5, and 6)		2.375	2.500	2.625	V						
V _{ID}	Input differential voltage swing (single-ended)	$R_L = 100 \Omega$	300	600	900	mV						
V _{ICM}	Input common mode voltage	$R_L = 100 \Omega$	385	600	845	mV						
V _{OD}	Output differential voltage (single-ended)	$R_L = 100 \Omega$	400	600	820	mV						
ΔV _{OD}	Change in V _{OD} between high and low	$R_L = 100 \Omega$			75	mV						
V _{OCM}	Output common mode voltage	$R_L = 100 \Omega$	440	600	780	mV						
Δ V _{OCM}	Change in V _{OCM} between high and low	$R_L = 100 \Omega$			50	mV						
R _L	Receiver differential input resistor		90	100	110	Ω						

Table 5–14. 3.3-V PCI Specifications (Part 1 of 2)									
Symbol	Parameter Conditions Minimum Typical Maximum Unit								
V _{CCIO}	Output supply voltage		3.0	3.3	3.6	V			
V _{IH}	High-level input voltage		$0.5 \times V_{CCIO}$		V _{CCIO} + 0.5	V			

Table 5–65. EP2S180 Column Pins Global Clock Timing Parameters										
Davamatav	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
Parameter	Industrial	Commercial	Grade	Grade	Grade	Unit				
t _{CIN}	2.003	2.100	3.652	3.993	4.648	ns				
t _{COUT}	1.846	1.935	3.398	3.715	4.324	ns				
t _{PLLCIN}	-0.3	-0.29	0.053	0.054	0.058	ns				
t _{PLLCOUT}	-0.457	-0.455	-0.201	-0.224	-0.266	ns				

Table 5–66. EP2S180 Row Pins Regional Clock Timing Parameters										
Parameter	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
raiaillelei	Industrial	Commercial	Grade	Grade	Grade	Unit				
t _{CIN}	1.759	1.844	3.273	3.577	4.162	ns				
t _{COUT}	1.764	1.849	3.269	3.573	4.157	ns				
t _{PLLCIN}	-0.542	-0.541	-0.317	-0.353	-0.414	ns				
t _{PLLCOUT}	-0.537	-0.536	-0.321	-0.357	-0.419	ns				

Table 5–67. EP2S180 Row Pins Global Clock Timing Parameters										
Parameter	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
Farameter	Industrial	Commercial	Grade	Grade	Grade	Ullit				
t _{CIN}	1.763	1.850	3.285	3.588	4.176	ns				
t _{COUT}	1.768	1.855	3.281	3.584	4.171	ns				
t _{PLLCIN}	-0.542	-0.542	-0.319	-0.355	-0.42	ns				
t _{PLLCOUT}	-0.537	-0.537	-0.323	-0.359	-0.425	ns				

Table 5-73. Stra	tix II I/O Inpu	t Delay for Co	lumn Pins (Pa	art 2 of 3)				
I/O Standard	Parameter	Minimu	m Timing	-3 Speed Grade	-3 Speed Grade	-4 Speed	-5 Speed	Unit
i/O Stailualu	raiailietei	Industrial	Commercial	(2)	(3)	Grade	Grade	Oiiit
1.5-V HSTL	t _{P1}	560	587	993	1041	1141	1329	ps
Class II	t _{PCOUT}	294	308	557	584	640	746	ps
1.8-V HSTL	t _{Pl}	543	569	898	941	1031	1201	ps
Class I	t _{PCOUT}	277	290	462	484	530	618	ps
1.8-V HSTL	t _{Pl}	543	569	898	941	1031	1201	ps
Class II	t _{PCOUT}	277	290	462	484	530	618	ps
PCI	t _{Pl}	679	712	1214	1273	1395	1625	ps
	t _{PCOUT}	413	433	778	816	894	1042	ps
PCI-X	t _{Pl}	679	712	1214	1273	1395	1625	ps
	t _{PCOUT}	413	433	778	816	894	1042	ps
Differential	t _{Pl}	507	530	818	857	939	1094	ps
SSTL-2 Class I	t _{PCOUT}	241	251	382	400	438	511	ps
Differential	t _{Pl}	507	530	818	857	939	1094	ps
SSTL-2 Class II	t _{PCOUT}	241	251	382	400	438	511	ps
Differential	t _{Pl}	543	569	898	941	1031	1201	ps
SSTL-18 Class I	t _{PCOUT}	277	290	462	484	530	618	ps
Differential	t _{Pl}	543	569	898	941	1031	1201	ps
SSTL-18 Class II	t _{PCOUT}	277	290	462	484	530	618	ps
1.8-V Differential	t _{Pl}	543	569	898	941	1031	1201	ps
HSTL Class I (1)	t _{PCOUT}	277	290	462	484	530	618	ps
1.8-V Differential	t _{Pl}	543	569	898	941	1031	1201	ps
HSTL Class II (1)	t _{PCOUT}	277	290	462	484	530	618	ps
1.5-V Differential	t _{P1}	560	587	993	1041	1141	1329	ps
HSTL Class I (1)	t _{PCOUT}	294	308	557	584	640	746	ps
1.5-V Differential	t _{P1}	560	587	993	1041	1141	1329	ps
HSTL Class II (1)	t _{PCOUT}	294	308	557	584	640	746	ps

Table 5–75. Sti				•	, 	_			
I/O Standard	Drive Strength	Parameter	Industrial	m Timing Commercial	-3 Speed Grade	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit
1.8 V	2 mA	t _{OP}	1042	1093	2904	3048	3338	3472	ps
		t _{DIP}	1062	1115	2970	3118	3414	3562	ps
	4 mA	t _{OP}	1047	1098	2248	2359	2584	2698	ps
		t _{DIP}	1067	1120	2314	2429	2660	2788	ps
	6 mA	t _{OP}	974	1022	2024	2124	2326	2434	ps
		t _{DIP}	994	1044	2090	2194	2402	2524	ps
	8 mA	t _{OP}	976	1024	1947	2043	2238	2343	ps
		t _{DIP}	996	1046	2013	2113	2314	2433	ps
	10 mA	t _{OP}	933	978	1882	1975	2163	2266	ps
		t _{DIP}	953	1000	1948	2045	2239	2356	ps
	12 mA	t _{OP}	934	979	1833	1923	2107	2209	ps
	(1)	t _{DIP}	954	1001	1899	1993	2183	2299	ps
1.5 V	2 mA	t _{OP}	1023	1073	2505	2629	2879	3002	ps
		t _{DIP}	1043	1095	2571	2699	2955	3092	ps
	4 mA	t _{OP}	963	1009	2023	2123	2325	2433	ps
		t _{DIP}	983	1031	2089	2193	2401	2523	ps
	6 mA	t _{OP}	966	1012	1923	2018	2210	2315	ps
		t _{DIP}	986	1034	1989	2088	2286	2405	ps
	8 mA (1)	t _{OP}	926	971	1878	1970	2158	2262	ps
		t _{DIP}	946	993	1944	2040	2234	2352	ps
SSTL-2 Class I	8 mA	t _{OP}	913	957	1715	1799	1971	2041	ps
		t _{DIP}	933	979	1781	1869	2047	2131	ps
	12 mA	t _{OP}	896	940	1672	1754	1921	1991	ps
	(1)	t _{DIP}	916	962	1738	1824	1997	2081	ps
SSTL-2 Class II	16 mA	t _{OP}	876	918	1609	1688	1849	1918	ps
		t _{DIP}	896	940	1675	1758	1925	2008	ps
	20 mA	t _{OP}	877	919	1598	1676	1836	1905	ps
		t _{DIP}	897	941	1664	1746	1912	1995	ps
	24 mA	t _{OP}	872	915	1596	1674	1834	1903	ps
	(1)	t _{DIP}	892	937	1662	1744	1910	1993	ps

Table 5–75. St	Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 8 of 8)										
	ъ.		Minimur	n Timing	-3	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade			
I/O Standard	Drive Strength	Parameter	Industrial	Commercial	Speed Grade (3)				Unit		
1.5-V	16 mA	t _{OP}	881	924	1431	1501	1644	1734	ps		
Differential HSTL Class II		t _{DIP}	901	946	1497	1571	1720	1824	ps		
	18 mA	t _{OP}	884	927	1439	1510	1654	1744			
		t _{DIP}	904	949	1505	1580	1730	1834			
	20 mA	t _{OP}	886	929	1450	1521	1666	1757			
		t _{DIP}	906	951	1516	1591	1742	1847			

Notes to Table 5–75:

- (1) This is the default setting in the Quartus II software.
- (2) These I/O standards are only supported on DQS pins.
- (3) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (4) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

Table 5–76. Stratix II I/O Output Delay for Row Pins (Part 1 of 3)											
			Minimu	m Timing	-3	-3	-4 Speed Grade	-5			
I/O Standard	Drive Strength	Parameter	Industrial	Commercial	Speed Grade (2)	Speed Grade (3)		Speed Grade	Unit		
LVTTL	4 mA	t _{OP}	1267	1328	2655	2786	3052	3189	ps		
		t _{DIP}	1225	1285	2600	2729	2989	3116	ps		
	8 mA	t _{OP}	1144	1200	2113	2217	2429	2549	ps		
		t _{DIP}	1102	1157	2058	2160	2366	2476	ps		
	12 mA	t _{OP}	1091	1144	2081	2184	2392	2512	ps		
	(1)	t _{DIP}	1049	1101	2026	2127	2329	2439	ps		
LVCMOS	4 mA	t _{OP}	1144	1200	2113	2217	2429	2549	ps		
		t _{DIP}	1102	1157	2058	2160	2366	2476	ps		
	8 mA (1)	t _{OP}	1044	1094	1853	1944	2130	2243	ps		
		t _{DIP}	1002	1051	1798	1887	2067	2170	ps		

Table 5–80. Maximum DCD for Non-DDIO Output on Row I/O Pins (Part 2of 2)Note (1)										
Row I/O Output	Maximu	n DCD for Non-DDIO	Output							
Standard	-3 Devices	-4 & -5 Devices	Unit							
1.8 V	180	180	ps							
1.5-V LVCMOS	165	195	ps							
SSTL-2 Class I	115	145	ps							
SSTL-2 Class II	95	125	ps							
SSTL-18 Class I	55	85	ps							
1.8-V HSTL Class I	80	100	ps							
1.5-V HSTL Class I	85	115	ps							
LVDS/ HyperTransport technology	55	80	ps							

Note to Table 5-80:

(1) The DCD specification is based on a no logic array noise condition.

Here is an example for calculating the DCD as a percentage for a non-DDIO output on a row I/O on a -3 device:

If the non-DDIO output I/O standard is SSTL-2 Class II, the maximum DCD is 95 ps (see Table 5–80). If the clock frequency is 267 MHz, the clock period T is:

$$T = 1/f = 1/267 \text{ MHz} = 3.745 \text{ ns} = 3745 \text{ ps}$$

To calculate the DCD as a percentage:

$$(T/2 - DCD) / T = (3745ps/2 - 95ps) / 3745ps = 47.5\%$$
 (for low boundary)

$$(T/2 + DCD) / T = (3745ps/2 + 95ps) / 3745ps = 52.5\%$$
 (for high boundary)